Search Notes

Application/Control No.	Appl Reex
10/021 719	TAN

Examiner

DUNG A. LE

Applicant(s)/Patent under Reexamination TANAKA, KOICHIRO

Art Unit

2818

SEARCHED				
Class	Subclass	Date	Examiner	
438	166	3/18/2005	DLE	
	487			
	308			
	378			
	795			
219	121.65			
	121.76			
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

(INCLUDING SEARCH	STRATEGY)
	DATE	EXMR
IEEE,PGPUB,JPO,EPO,EAST, IMB	3/18/2005	DLE .
438/166,306,378,795 Interference search	10/28/2005	DLE
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